

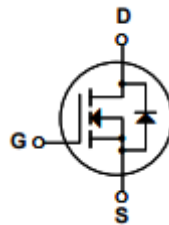
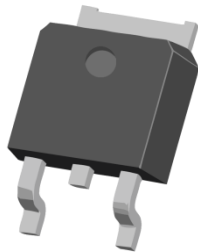
Description

This N-channel MOSFETS use advanced trench technology and design to provide excellent RDS(on) with low gate charge. It can be used in a wide variety of applications.

Features

BVDSS	RDS(ON)	ID
600V	1.2Ω	7A

- 1) Low gate charge.
- 2) Green device available.
- 3) Advanced high cell density trench technology for ultra RDS(ON)
- 4) Excellent package for good heat dissipation.



TO-252

Absolute Maximum Ratings $T_c=25^{\circ}\text{C}$, unless otherwise noted

Symbol	Parameter	Ratings	Units
VDS	Drain-Source Voltage	600	V
VGS	Gate-Source Voltage	±20	V
ID	Continuous Drain Current-1	7	A
	Continuous Drain Current-T=100°C	2.4	
	Pulsed Drain Current ²	16	
EAS	Single Pulse Avalanche Energy ³	300	mJ
PD	Power Dissipation ⁴	80	W
TJ, TSTG	Operating and Storage Junction Temperature Range	-55 to +150	°C

Thermal Characteristics

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Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case1	1.58	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient1	110	

Package Marking and Ordering Information

Part NO.	Marking	Package
KSMD7N60	KSMD7N60	TO-252

Electrical Characteristics $T_c=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{DS}=0V, I_D=250\mu A$	600	—	—	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=0V, V_{GS}=32V$	—	—	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{DS}=\pm 20V, V_{GS}=0A$	—	—	± 100	nA
On Characteristics						
$V_{GS(th)}$	GATE-Source Threshold Voltage	$V_{DS}=V_{DS}, I_D=250\mu A$	2.0	—	4.0	V
$R_{DS(on)}$	Drain-Source On Resistance ²	$V_{DS}=10V, I_D=6A$	—	1.7	1.2	Ω
		$V_{DS}=2.5V, I_D=5A$	—	—	—	
G_{FS}	Forward Transconductance	$V_{DS}=5V, I_D=12A$	—	4.8	—	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=15V, V_{GS}=0V,$ $f=1MHz$	—	620	810	pF
C_{oss}	Output Capacitance		—	65	85	
C_{rss}	Reverse Transfer Capacitance		—	7	10	
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DS}=20V,$ $V_{GS}=10V, R_{GEN}=3.3\Omega$	—	15	40	ns
t_r	Rise Time		—	45	100	ns
$t_{d(off)}$	Turn-Off Delay Time	$V_{GS}=4.5V, V_{DS}=20V,$ $I_D=6A$	—	45	100	ns
t_f	Fall Time		—	45	100	ns
Q_g	Total Gate Charge	$V_{GS}=4.5V, V_{DS}=20V,$ $I_D=6A$	—	16	20	nC
Q_{gs}	Gate-Source Charge		—	3.5	—	nC
Q_{gd}	Gate-Drain "Miller" Charge		—	6.5	—	nC
Drain-Source Diode Characteristics						
V_{SD}	Source-Drain Diode Forward Voltage ²	$V_{GS}=0V, I_S=1A$	—	—	1.4	V
t_{rr}	Reverse Recovery Time	$I_F=7A, di/dt=100A/\mu S$	—	310	—	ns
Q_{rr}	Reverse Recovery Charge		—	2.1	—	nC

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Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board 2OZ copper.
2. The data tested by pulse width≤300us,duty cycle≤2%
3. The EAS data shows Max. rating. The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=17.8A$
4. The power dissipation is limited by 150°C junction temperature.

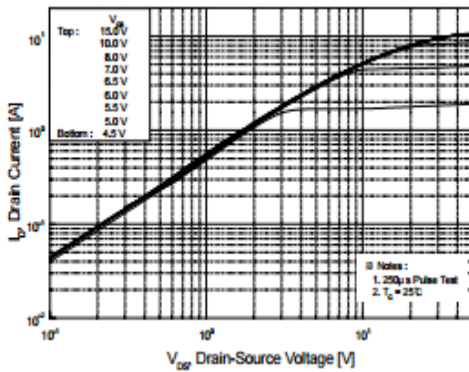
Typical Characteristics $T_J=25^{\circ}C$ unless otherwise noted


Figure 1. On-Region Characteristics

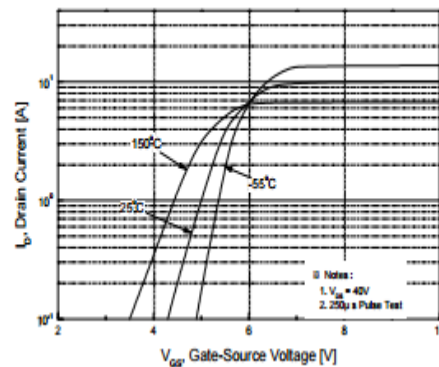


Figure 2. Transfer Characteristics

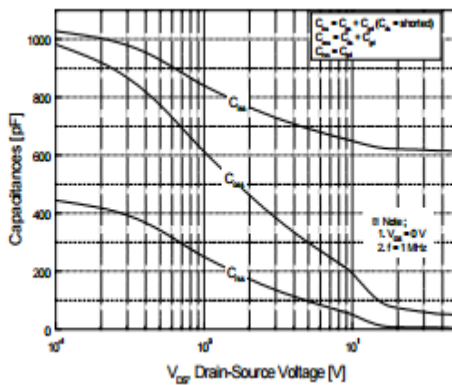


Figure 3. Capacitance Characteristics

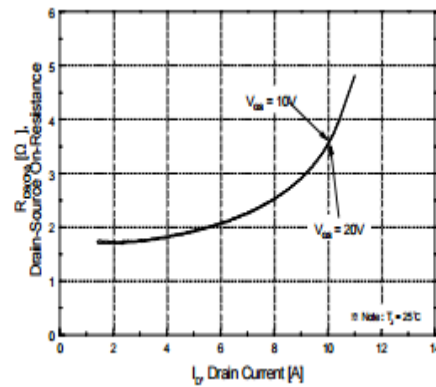
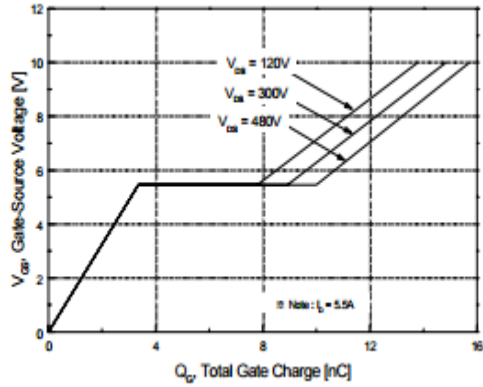
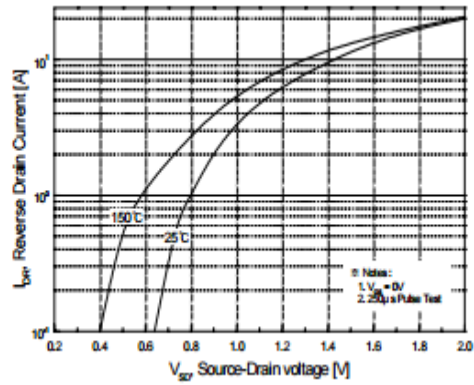
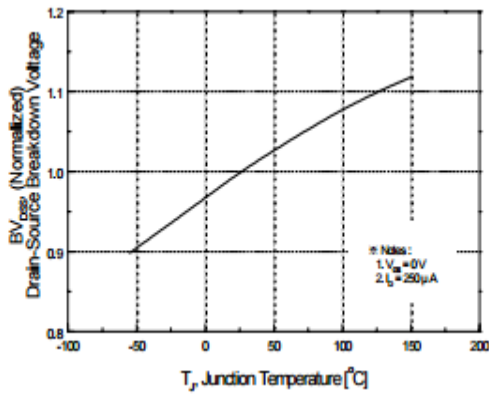
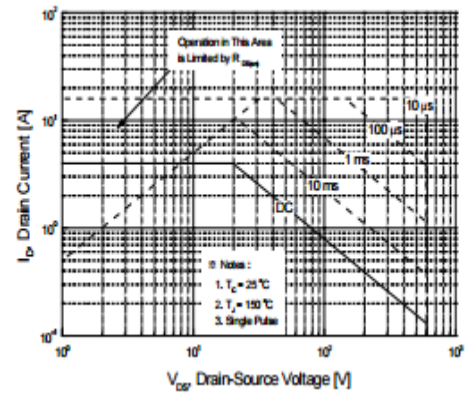
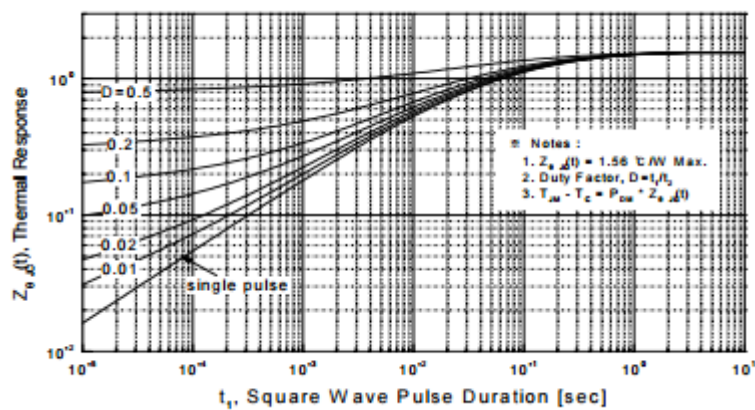


Figure 4. On-Resistance Variation vs. Drain Current and Gate Voltage

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Figure 5. Gate Charge Characteristics

Figure 6. Body Diode Forward Voltage Variation vs. Source Current and Temperature

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. Maximum Safe Operating Area

Figure 9. Transient Thermal Response Curve